

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant : Albert Birner et al. Art Unit : Unknown
Serial No. : Examiner : Unknown
Filed : July 30, 2003
Title : SEMICONDUCTOR TRENCH STRUCTURE

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

INFORMATION DISCLOSURE STATEMENT


Copies of the foreign patents listed on the attached form PTO-1449 are enclosed. A copy of a communication from the German Patent Office in counterpart application DE 102 34 952.5 is also enclosed. Pursuant to 37 CFR § 1.98(a)(2)(i), copies of the U.S. patents are no longer necessary.

This statement is being filed with the application. I, the undersigned, hereby certify that the foreign patents contained in this statement were cited in a communication from a foreign patent office in a counterpart foreign application, the communication being dated April 2, 2003. Please apply any charges to Deposit Account No. 06-1050, referencing Attorney Docket No. 12816-095001.

Respectfully submitted,

Date: _____

July 30, 2003



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Substitute Form PTO-1449 (Modified) Information Disclosure Statement by Applicant (Use several sheets if necessary) (37 CFR §1.98(b))	U.S. Department of Commerce Patent and Trademark Office	Attorney's Docket No. 12816-095001	Application No.
	Applicant Albert Birner et al.		
	Filing Date July 30, 2003	Group Art Unit	

U.S. Patent Documents							
Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
	AA	6,528,384	Dec. 27, 2001	Beckmann et al. (English Equivalent of DE 100 14 920 C1)			
	AB	6,455,369	Sep. 24, 2002	Forster et al. (English Equivalent of DE 100 40 464 A1)			
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						

Foreign Patent Documents or Published Foreign Patent Applications								
Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclass	Translation	
							Yes	No
	AL	100 40 464 A1	Feb. 2, 2002	DE			Abst.	
	AM	100 14 920 C1	Jul. 26, 2001	DE			Abst.	
	AN							
	AO							
	AP							

Other Documents (include Author, Title, Date, and Place of Publication)		
Examiner Initial	Desig. ID	Document
	AQ	
	AR	
	AS	

Examiner Signature	Date Considered
EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	